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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/696,759	10/29/2003	Fang-Zhong Chen	15436.247.5.1	7926
22913 7590 08/03/2007 WORKMAN NYDEGGER (F/K/A WORKMAN NYDEGGER & SEELEY) 60 EAST SOUTH TEMPLE 1000 EAGLE GATE TOWER SALT LAKE CITY, UT 84111			EXAMINER PATEL, PARESH H	
			ART UNIT 2829	PAPER NUMBER
			MAIL DATE 08/03/2007	DELIVERY MODE PAPER

**Please find below and/or attached an Office communication concerning this application or proceeding.**

The time period for reply, if any, is set in the attached communication.

**Office Action Summary**

Application No.

10/696,759

Applicant(s)

CHEN ET AL.

Examiner

Paresh Patel

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-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address --

**Period for Reply**

A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) OR THIRTY (30) DAYS, WHICHEVER IS LONGER, FROM THE MAILING DATE OF THIS COMMUNICATION.

- Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication.
- If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication.
- Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).

**Status**

- 1) ☒ Responsive to communication(s) filed on 21 May 2007.
- 2a) ☐ This action is FINAL. 2b) ☒ This action is non-final.
- 3) ☐ Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under *Ex parte Quayle*, 1935 C.D. 11, 453 O.G. 213.

**Disposition of Claims**

- 4) ☒ Claim(s) 1-26 is/are pending in the application.
- 4a) Of the above claim(s) 6-24 and 26 is/are withdrawn from consideration.
- 5) ☐ Claim(s) \_\_\_\_\_ is/are allowed.
- 6) ☒ Claim(s) 1-5, 25 is/are rejected.
- 7) ☐ Claim(s) \_\_\_\_\_ is/are objected to.
- 8) ☐ Claim(s) \_\_\_\_\_ are subject to restriction and/or election requirement.

**Application Papers**

- 9) ☒ The specification is objected to by the Examiner.
- 10) ☐ The drawing(s) filed on \_\_\_\_\_ is/are: a) ☐ accepted or b) ☐ objected to by the Examiner.  
Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).  
Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).
- 11) ☐ The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.

**Priority under 35 U.S.C. § 119**

- 12) ☐ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
- a) ☐ All b) ☐ Some \* c) ☐ None of:
1. ☐ Certified copies of the priority documents have been received.
2. ☐ Certified copies of the priority documents have been received in Application No. \_\_\_\_\_.
3. ☐ Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).
- \* See the attached detailed Office action for a list of the certified copies not received.

**Attachment(s)**

- 1) ☒ Notice of References Cited (PTO-892)
- 2) ☐ Notice of Draftsperson's Patent Drawing Review (PTO-948)
- 3) ☐ Information Disclosure Statement(s) (PTO/SB/08)  
Paper No(s)/Mail Date \_\_\_\_\_
- 4) ☐ Interview Summary (PTO-413)  
Paper No(s)/Mail Date. \_\_\_\_\_
- 5) ☐ Notice of Informal Patent Application.
- 6) ☐ Other: \_\_\_\_\_

## DETAILED ACTION

### *Election/Restrictions*

1. Applicant's election without traverse of Group I (claims 1-5 and 25) in the reply filed on 05/21/2007 is acknowledged.

### *Claim Rejections - 35 USC § 103*

2. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negated by the manner in which the invention was made.

3. Claims 1-5 and 25 are rejected under 35 U.S.C. 103(a) as being unpatentable over Monson et al. (US 7135704).

Regarding claim 1, Monson et al. (hereafter Monson) in fig. 1-16 discloses a system for testing optoelectronic devices, the system comprising:

a burn-in rack [102] mountable within a support structure [104], said burn-in rack supports a plurality of optoelectronic devices [240] during burn-in testing and life testing [see Abstract], said burn-in rack with said plurality of optoelectronic devices being disposable in either a burn-in oven or within said support structure for life testing [see Abstract]; and

an optical detector assembly comprising a plurality of detectors [optical sensors, see lines 18-25 of col. 4].

Monson is silent about said optical detector assembly **mounted** to said support structure, each of said plurality of detectors **aligning** with one of said plurality of optoelectronic devices to detect an output of each of said plurality of optoelectronic devices during the testing. Monson uses plurality of optical sensors positioned proximate rear cover surface of a support structure 104 to allow laser amplitude and other characteristic to be measured during the burn-in process. Therefore, it would have been obvious to one having ordinary skill in the art at the time the invention was made to mount the optical detectors with support structure and to align said plurality of optical detectors with one of said plurality of optoelectronic devices, in order to measure the electrical characteristic during simultaneous testing of each of the plurality of optoelectronic devices [see lines 18-25 of column 4 and the Abstract].

Regarding claim 2, Monson discloses a system as recited in claim 1, wherein said system further comprising a computer [controller as further disclosed] in electrical communication with at least one of said burn-in rack and said detector assembly.

Regarding claim 3, Monson discloses a system as recited in claim 2, wherein said computer controls said life testing and said burn-in testing [see Abstract].

Regarding claim 4, Monson discloses a system as recited in claim 1, wherein said burn-in rack comprises:

- a rack base [base of 102] that supports a circuit board [114]; and
- at least one diode support [108] disposed from and supported by said rack base, said at least one diode support supporting said plurality of optoelectronic devices [240].

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Regarding claim 5, Monson discloses all the elements including plurality of detectors [optical sensors]. Monson is silent about said plurality of detectors are organized in an array. It would have been obvious for a person having ordinary skill in the art at the time the invention was made to organize detectors in an array, so electrical measurement of individual optoelectronic devices can be made simultaneously [see lines 18-25 of col. 4].

Regarding claim 25, Monson discloses the optical detector assembly is configured to simultaneously test the plurality of optoelectronic devices during burn-in testing and life testing [see lines 18-25 of col. 4].

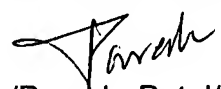
### ***Conclusion***

4. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Paresh Patel whose telephone number is 571-272-1968. The examiner can normally be reached on 8:00 to 4:30pm.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Ha Nguyen can be reached on 571-272-1678. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

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Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

 08/01/07  
/Paresh Patel/  
Primary Examiner  
Art Unit 2829

August 01, 2007